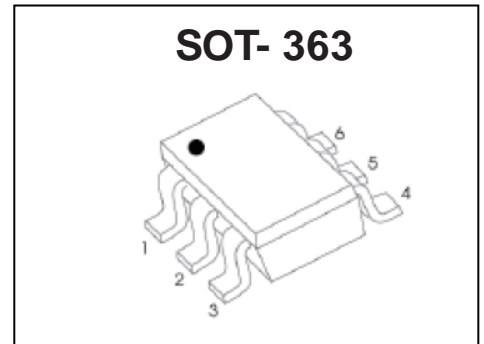


## N channel+P Channel MOS FET

$V_{(BR)DSS}$	$R_{DS(on)MAX}$	$I_D$
20V	380mΩ@4.5V	0.75A
	450mΩ@2.5V	
	800mΩ@1.8V	
-20V	520mΩ@-4.5V	-0.66A
	700mΩ@-2.5V	
	950mΩ@-1.8V	



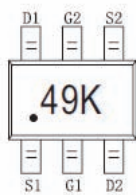
### FEATURE

- Surface Mount Package
- Low  $R_{DS(on)}$
- Operated at Low Logic Level Gate Drive
- ESD Protected Gate
- Including a N-ch FTK3134K and a P-ch FTK3139K (independently) In a Package

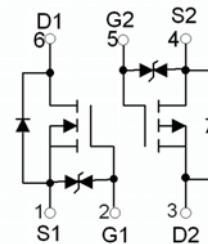
### APPLICATION

- Load/ Power Switching
- Interfacing Switching
- Battery Management for Ultra Small Portable Electronics
- Logic Level Shift

### MARKING



### Equivalent Circuit



### ABSOLUTE MAXIMUM RATINGS ( $T_a=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Value	Unit
<b>N- MOSFET</b>			
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	±12	V
Continuous Drain Current (note 1)	$I_D$	0.75	A
Pulsed Drain Current ( $t_p=10\mu\text{s}$ )	$I_{DM}$	1.8	A
<b>P- MOSFET</b>			
Drain-Source Voltage	$V_{DS}$	-20	V
Gate-Source Voltage	$V_{GS}$	±12	V
Continuous Drain Current (note 1)	$I_D$	-0.66	A
Pulsed Drain Current ( $t_p=10\mu\text{s}$ )	$I_{DM}$	-1.2	A
<b>Temperature and Thermal Resistance</b>			
Thermal Resistance from Junction to Ambient (note 1)	$R_{\theta JA}$	833	$^\circ\text{C/W}$
Junction Temperature	$T_J$	150	$^\circ\text{C}$
Storage Temperature	$T_{STG}$	-55~+150	$^\circ\text{C}$
Lead Temperature for Soldering Purposes(1/8" from case for 10 s)	$T_L$	260	$^\circ\text{C}$



## Electrical characteristics (T<sub>a</sub>=25°C unless otherwise noted)

### N-ch MOSFET

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>STATIC CHARACTERISTICS</b>						
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	20			V
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V			1	μA
Gate-body leakage current	I <sub>GSS</sub>	V <sub>GS</sub> = ±12V, V <sub>DS</sub> = 0V			±50	uA
Gate threshold voltage (note 2)	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	0.35		1	V
Drain-source on-resistance(note 2)	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 0.65A			380	mΩ
		V <sub>GS</sub> = 2.5V, I <sub>D</sub> = 0.55A			450	mΩ
		V <sub>GS</sub> = 1.8V, I <sub>D</sub> = 0.45A			800	mΩ
Forward transconductance(note 2)	g <sub>FS</sub>	V <sub>DS</sub> = 10V, I <sub>D</sub> = 0.8A		1.6		S
Diode forward voltage	V <sub>SD</sub>	I <sub>S</sub> = 0.15A, V <sub>GS</sub> = 0V			1.2	V
<b>DYNAMIC CHARACTERISTICS (note 4)</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 16V, V <sub>GS</sub> = 0V, f = 1MHz		79	120	pF
Output Capacitance	C <sub>oss</sub>			13	20	pF
Reverse Transfer Capacitance	C <sub>rss</sub>			9	15	pF
<b>SWITCHING CHARACTERISTICS (note 3,4)</b>						
Turn-on delay time	t <sub>d(on)</sub>	V <sub>GS</sub> = 4.5V, V <sub>DS</sub> = 10V, I <sub>D</sub> = 500mA, R <sub>GEN</sub> = 10Ω		6.7		ns
Turn-on rise time	t <sub>r</sub>			4.8		ns
Turn-off delay time	t <sub>d(off)</sub>			17.3		ns
Turn-off fall time	t <sub>f</sub>			7.4		ns

### P-ch MOSFET

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>STATIC CHARACTERISTICS</b>						
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250μA	-20			V
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V			-1	μA
Gate-body leakage current	I <sub>GSS</sub>	V <sub>GS</sub> = ±12V, V <sub>DS</sub> = 0V			±20	uA
Gate threshold voltage (note 2)	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA	-0.35		-1.1	V
Drain-source on-resistance(note 2)	R <sub>DS(on)</sub>	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -1A			520	mΩ
		V <sub>GS</sub> = -2.5V, I <sub>D</sub> = -0.8A			700	mΩ
		V <sub>GS</sub> = -1.8V, I <sub>D</sub> = -0.5A			950	mΩ
Forward transconductance(note 2)	g <sub>FS</sub>	V <sub>DS</sub> = -10V, I <sub>D</sub> = -0.54A		1.2		S
Diode forward voltage	V <sub>SD</sub>	I <sub>S</sub> = -0.5A, V <sub>GS</sub> = 0V			-1.2	V
<b>DYNAMIC CHARACTERISTICS (note 4)</b>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = -16V, V <sub>GS</sub> = 0V, f = 1MHz		113	170	pF
Output Capacitance	C <sub>oss</sub>			15	25	pF
Reverse Transfer Capacitance	C <sub>rss</sub>			9	15	pF
<b>SWITCHING CHARACTERISTICS (note 3, 4)</b>						
Turn-on delay time	t <sub>d(on)</sub>	V <sub>GS</sub> = -4.5V, V <sub>DS</sub> = -10V, I <sub>D</sub> = -200mA, R <sub>GEN</sub> = 10Ω		9		ns
Turn-on rise time	t <sub>r</sub>			5.8		ns
Turn-off delay time	t <sub>d(off)</sub>			32.7		ns
Turn-off fall time	t <sub>f</sub>			20.3		ns

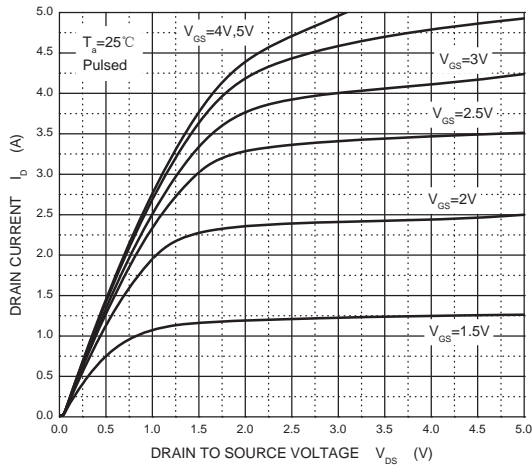
#### Notes :

1. Surface mounted on FR4 board using the minimum recommended pad size.
2. Pulse Test : Pulse width = 300μs, duty cycle ≤ 2%.
3. Switching characteristics are independent of operating junction temperature.
4. Guaranteed by design, not subject to producing.

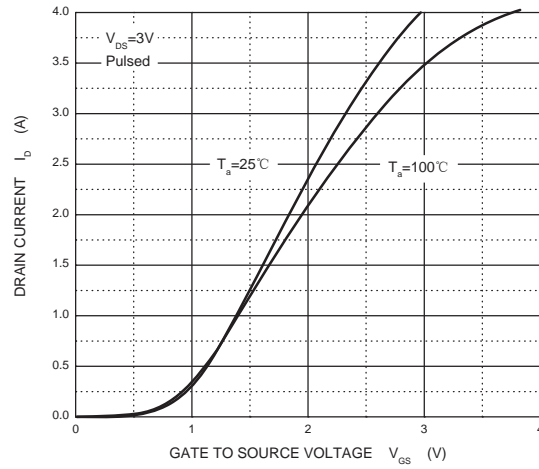
## Typical Characteristics

N-Channel MOS

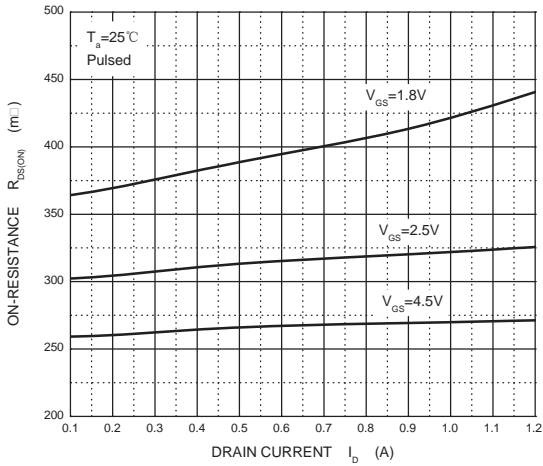
Output Characteristics



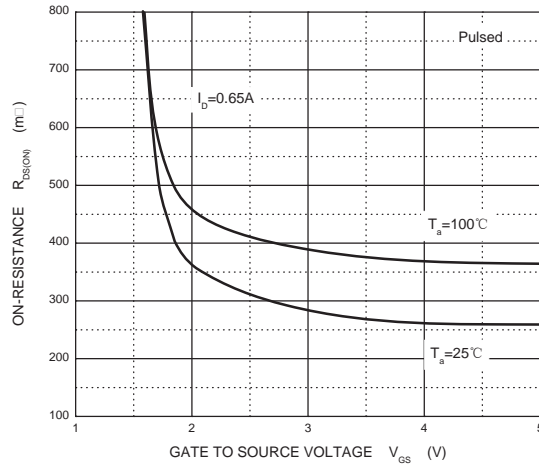
Transfer Characteristics



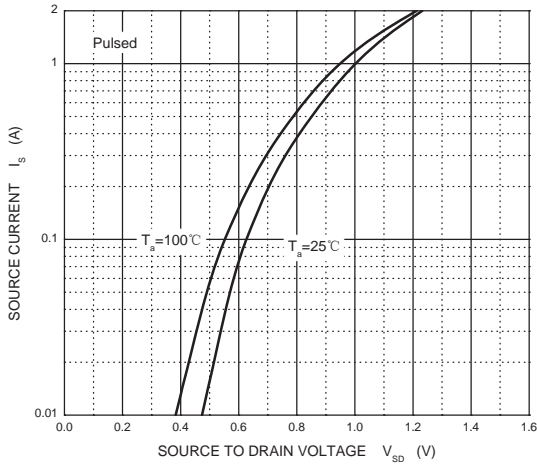
$R_{DS(ON)}$  —  $I_D$



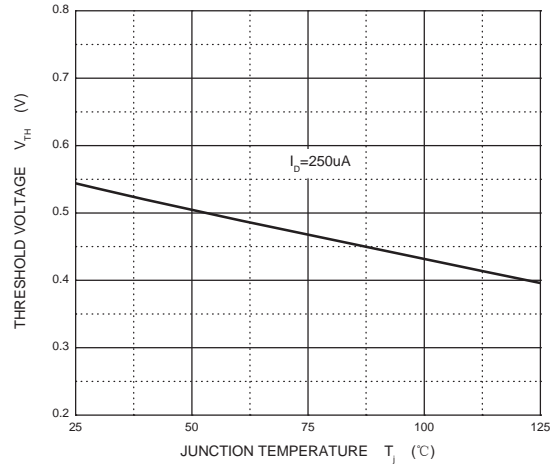
$R_{DS(ON)}$  —  $V_{GS}$



$I_S$  —  $V_{SD}$



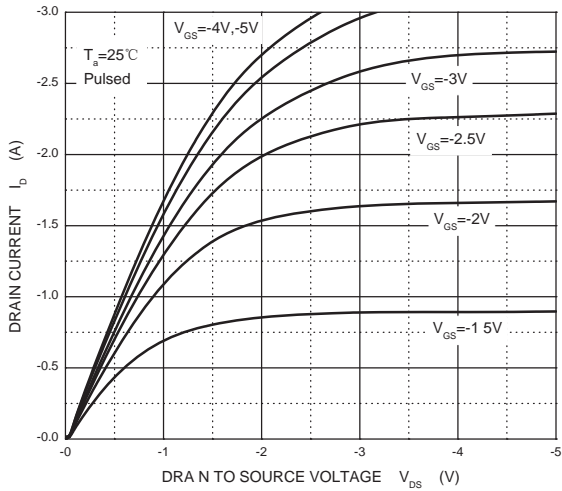
Threshold Voltage



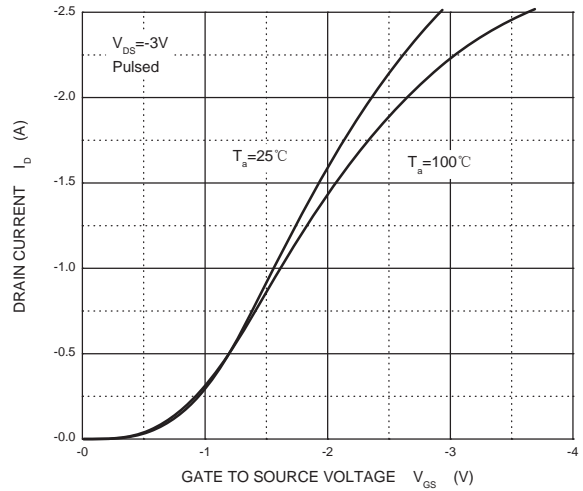


## P-Channel MOS

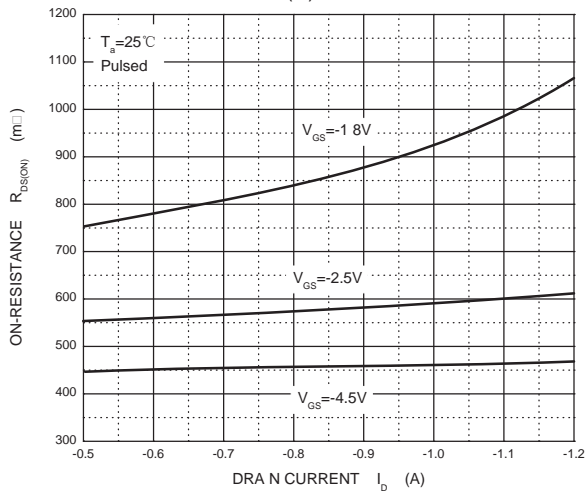
Output Characteristics



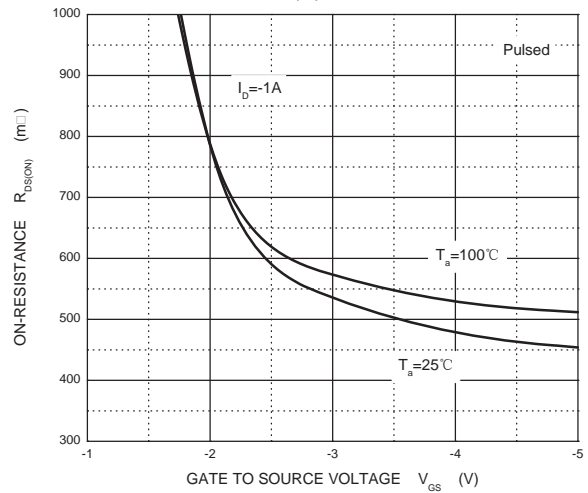
Transfer Characteristics



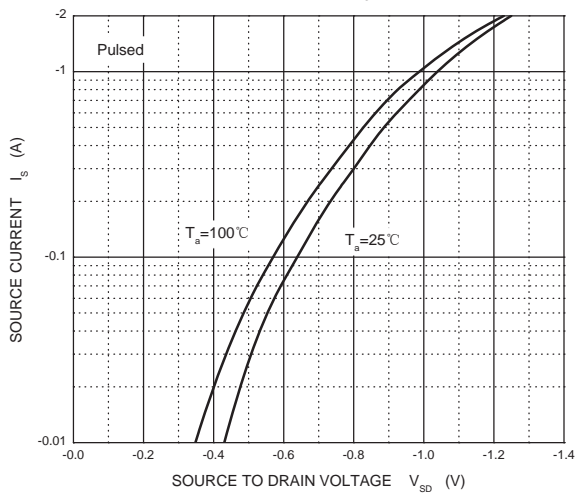
$R_{DS(ON)}$  —  $I_D$



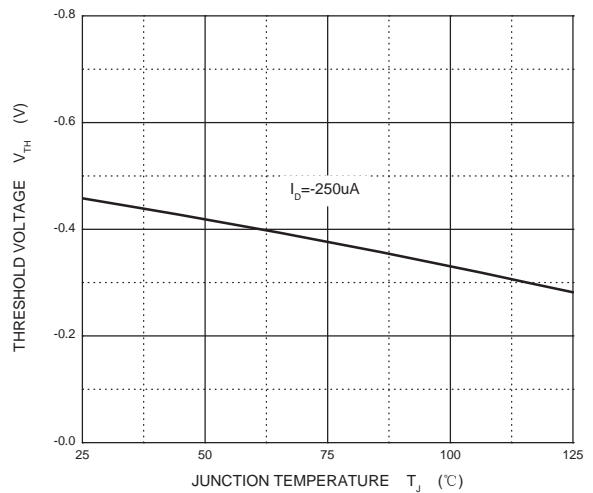
$R_{DS(ON)}$  —  $V_{GS}$



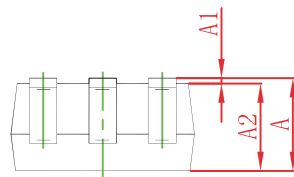
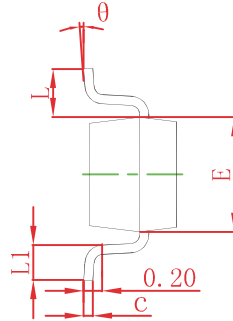
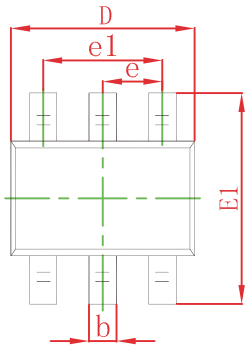
$I_S$  —  $V_{SD}$



Threshold Volt age

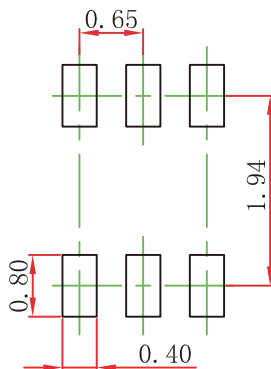


## SOT-363 Package Outline Dimensions



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	0.900	1.100	0.035	0.043
A1	0.000	0.100	0.000	0.004
A2	0.900	1.000	0.035	0.039
b	0.150	0.350	0.006	0.014
c	0.080	0.150	0.003	0.006
D	2.000	2.200	0.079	0.087
E	1.150	1.350	0.045	0.053
E1	2.150	2.450	0.085	0.096
e	0.650 TYP		0.026 TYP	
e1	1.200	1.400	0.047	0.055
L	0.525 REF		0.021 REF	
L1	0.260	0.460	0.010	0.018
$\theta$	0°	8°	0°	8°

## SOT-363 Suggested Pad Layout



**Note:**

1. Controlling dimension: in millimeters.
2. General tolerance:  $\pm 0.05\text{mm}$ .
3. The pad layout is for reference purposes only.